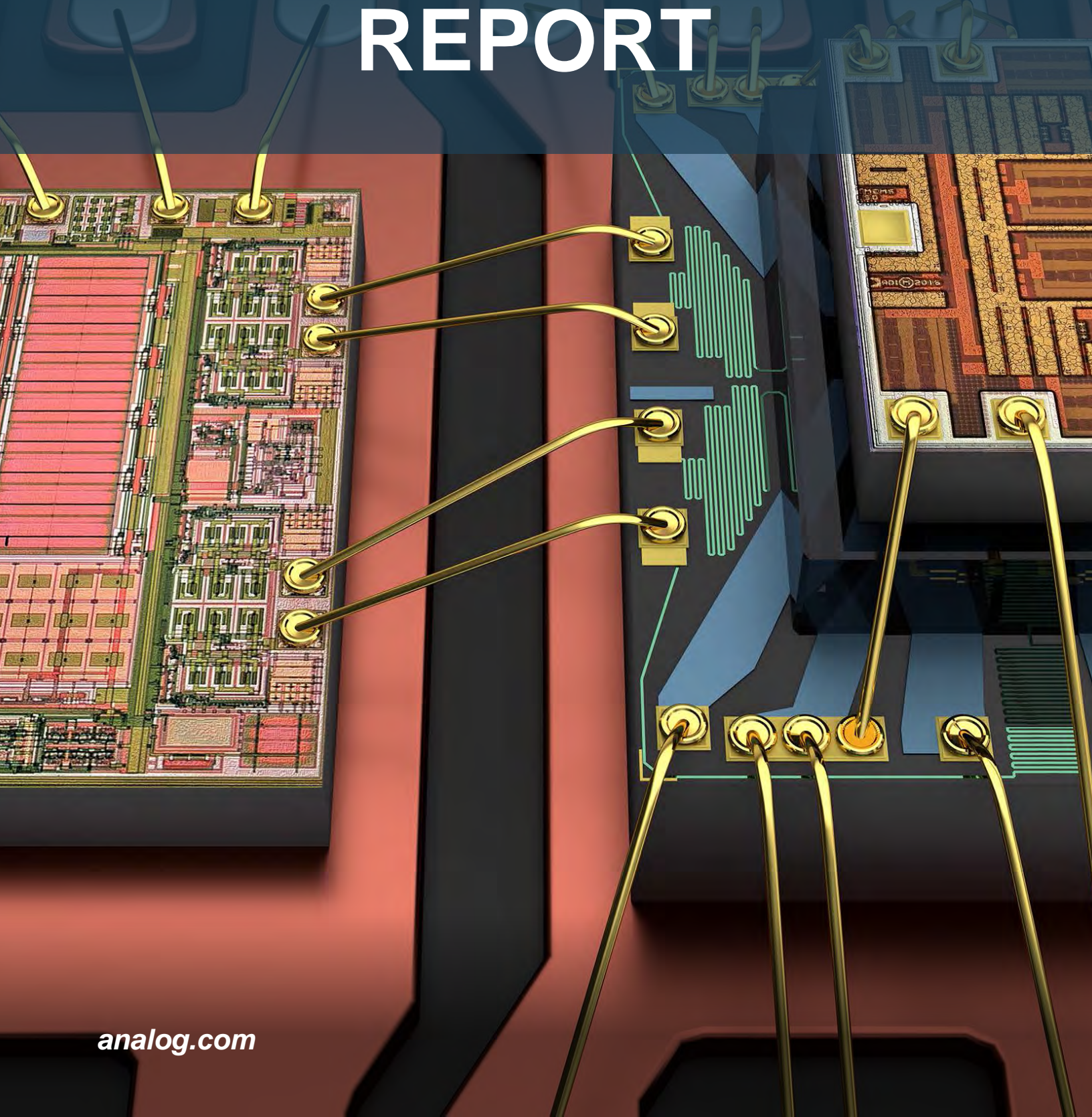


RELIABILITY REPORT





NOW PART OF



Reliability Data Report

Product Family R552

LT6654 / LT6656 / LT6657 / LT6658

Reliability Data Report

Report Number: R552

Report generated on: Mon Mar 05 11:03:09 PST 2018

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) ¹	No. of FAILURES _{2,3}
LCC	231	1138	1313	585	0
SOIC/MSOP	77	1503	1503	129	0
SOT	853	0935	1406	646	0
Totals	1,161	-	-	1,360	0

HIGHLY ACCELERATED STRESS TEST AT +130 DEG C / 85% RH					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+85°C) ⁴	No. of FAILURES
SOIC/MSOP	240	1452	1544	460	0
SOT	541	1010	1406	2093	0
Totals	781	-	-	2,553	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	703	1245	1707	16	0
SOIC/MSOP	231	1452	1544	77	0
SOT	4074	0946	1708	152	0
Totals	5,008	-	-	245	0

TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	748	1105	1707	74	0
LCC	231	1047	1209	192	0
SOIC/MSOP	231	1452	1544	115	0
SOT	4471	0946	1708	655	0
Totals	5,681	-	-	1,036	0

THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	697	1245	1707	69	0
LCC	228	1104	1209	189	0
SOT	4413	0946	1708	647	0
Totals	5,338	-	-	905	0

(1) Assumes Activation Energy = 1.0 Electron Volts
(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =1.35 FITS
(3) Mean Time Between Failure in Years = 84688.7
(4) Assumes 20X Acceleration from 85 °C to +130 °C
Note 1: 1 FIT = 1 Failure in One Billion Hours.
Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL Preconditioning

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HIGH TEMPERATURE BAKE AT 175 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
LCC	154	1209	1216	115	0
SOT	154	1313	1313	154	0
Totals	308	-	-	269	0
HIGH TEMPERATURE BAKE AT 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	485	1245	1618	485	0
LCC	77	1049	1049	77	0
SOIC/MSOP	129	1452	1544	129	0
SOT	154	1010	1010	154	0
Totals	845	-	-	845	0
MECHANICAL SHOCK (JESD22-B104 CONDITION B - PEAK = 1500G)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		No. of FAILURES
LCC	40	1049	1209		0
Totals	40	-	-		0
VIBRATION VARIABLE FREQUENCY (JESD22-B103 CONDITION A - PEAK = 20G)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		No. of FAILURES
LCC	40	1049	1209		0
Totals	40	-	-		0